

<p>Keynotes</p> <p>New developments in X-ray CT metrology for Industry 4.0 <i>Prof. Wim Dewulf, KU Leuven, BE</i></p> <p>New applications of X-ray CT to characterisation and failure analysis in composite materials <i>Prof. Ian Sinclair, University of Southampton, UK</i></p>
<p>Session “New Methods & Optimization” - Oral contributions</p> <p>Helical XCT measurement for correlative imaging <i>Adam Brinek, Brno University of Technology, CZ</i></p> <p>Spatial Resolution Enhancement Based on Detector Displacement for Computed Tomography <i>Kaicong Sun, University of Stuttgart, DE</i></p> <p>Scatter Correction for Industrial Cone-Beam Computed Tomography (CBCT) Using VSHARP, a fast GPU-Based Linear Boltzmann Transport Equation Solver <i>Amy Shiroma, Varex Imaging Corporation, USA</i></p> <p>Artifact reduction in X-ray computed tomography by multipositional data fusion using local image quality measures <i>Gabriel Herl, Fraunhofer Entwicklungszentrum Röntgentechnik, DE</i></p> <p>Flexible solutions for lab-based phase contrast and dark field CT and micro-CT <i>Alessandro Olivo, University College London, UK</i></p> <p>Simulated Talbot-interferometer x-ray phase contrast images with CFRP-like objects <i>Jonathan Sanctorum, University of Antwerp, BE</i></p>
<p>Session “Algorithms & Reconstruction” - Oral contributions</p> <p>An Interactive Visual Comparison Tool for 3D Volume Datasets represented by Nonlinearly Scaled 1D Line Plots through Space-filling Curves <i>Johannes Weissenböck, University of Applied Sciences Upper Austria, AU</i></p> <p>Virtual CT of complex and noisy scanning trajectories using aRTist <i>Carsten Bellon, Bundesanstalt für Materialforschung und -prüfung, DE</i></p> <p>Strategies in cone beam CT inspection of cylindrical objects <i>Wannes Goethals, Ghent University, BE</i></p> <p>Accurate surface extraction on CT volume using analytical gradient of FDK formula <i>Yukie Nagai, The University of Tokyo, JP</i></p> <p>Digging Deeper into High Resolution X-ray Computed Tomography Reconstruction <i>Emre Topal, TU Dresden, Dresden Center for Nanoanalysis, DE</i></p>
<p>Session “Metrology” - Oral contributions</p> <p>Comparison of different measures for the single point uncertainty in industrial X-ray computed tomography <i>Andreas Michael Müller, Friedrich-Alexander-University Erlangen-Nuremberg, DE</i></p> <p>Software-based compensation of CT instrument misalignments <i>Evelina Ametova, Katholieke Universiteit Leuven, BE</i></p> <p>CT geometry determination using individual radiographs of calibrated multi-sphere standards <i>Benjamin A. Bircher, Federal Institute of Metrology METAS, CH</i></p> <p>Uncertainty for Uncorrected Measurement Results in X-ray Computed Tomography <i>Hermínso Villarraga-Gómez, Nikon Metrology, Inc., USA</i></p>
<p>Session “Metrology & Manufacturing” - Oral contributions</p> <p>Investigating of the influence of the workpiece placement on the uncertainty of measurements in the industrial computed tomography <i>Natalia Grozmani, RWTH Aachen University, DE</i></p> <p>Experimental investigation on the accuracy of CT measurement of fiber length in fiber reinforced polymers <i>Filippo Zanini, University of Padova, IT</i></p> <p>Sinogram interpolation to decrease acquisition time in X-ray computed tomography measurement of surface topography <i>Lars Körner, Univeristy of Nottingham, UK</i></p> <p>Uncertainty Evaluation of Pore Analysis for Additively Manufactured Parts using Cross Sections <i>Leonard Schild, wbk Institute of Production Science, Karlsruhe Institute of Technology (KIT), DE</i></p> <p>Characterization of resolution performance of novel high energy X-CT : eXTRACT <i>Katsutoshi Sato, Hitachi Ltd, JP</i></p>
<p>Session “NDT” - Oral contributions</p> <p>Fast detection of cracks in ultrasonically welded parts by inline X-ray inspection <i>Eline Janssens, imec - Vision Lab, BE</i></p> <p>Comparison of X-ray computed tomography and immersion ultrasonic non-destructive testing techniques in the case of qualitative and quantitative assessment of brazing quality level <i>Mariusz Jedrychowski, CERN, CH</i></p> <p>A Novel Approach for Immediate, Interactive CT Data Visualization and Evaluation using GPU-based Segmentation and Visual Analysis <i>Harald Steinlechner, VRVis Research Center, AU</i></p> <p>Virtual qualification of novel heat exchanger components with the image-based finite element method <i>Llion Evans, Swansea University, UK</i></p>

Session “Materials characterization” - Oral contributions

- MultiScale and MultiTime Image-Based Control and Characterization of Lithium-Ion Batteries and Materials**
Remi Blanc, Thermo Fisher Scientific, FR
- In-situ computed tomography investigation of the compression behaviour of strut, and periodic surface lattices**
Anton Jansson, Örebro University, SE
- X-ray microtomography study of pellet/powder bentonite mixture upon wetting**
Agustin Molinero Guerra, Ecole des Ponts ParisTech, CNRS, IFSTTAR, Laboratoire Navier/CERMES, FR
- Use of the industrial X-ray computed microtomography to address scientific questions in developmental biology**
Markéta Tesařová, Central European Institute of Technology, Brno University of Technology, CZ
- Quantitative pore network analysis and permeability evaluation of porous carbonate reservoir rocks using X-ray computed microtomography images**
Miller Zambrano, University of Camerino, GeoMORE s.r.l., IT

Session “NDT, Materials & Manufacturing” - Oral contributions

- Characterisation of fiber lay-up and defects in CFRP using Talbot-Lau grating interferometry**
Sascha Senck, University of Applied Sciences Upper Austria, AU
- Combining a Computed Laminography Approach with Tomographic Analysis for a Study of Weld Joints**
Marius Costin, The French Alternative Energies and Atomic Energy Commission (CEA), FR
- Defect detection in 3D printed carbon fibre composites using X-ray Computed Tomography**
Jeroen Soete, Katholieke Universiteit Leuven, BE
- Process characterization for moulding of paper bottles using computed tomography and structure tensor analysis**
Prateek Saxena, Technical University of Denmark, DK
- Methodology of precise In-Situ tensile/compression measurements**
Sebastian Wronski, AGH - University of Science and Technology, PL

Short Talks

- Generating Meaningful Synthetic Ground Truth for Pore Detection in Cast Aluminum Parts**
Patrick Fuchs, Interdisciplinary Center for Scientific Computing (IWR), Heidelberg University, DE
- Synchrotron based absorption edge tomography for the analysis of 3D printed polymer embedded MOF**
Christian Gollwitzer, Bundesanstalt für Materialforschung und -prüfung, DE
- Analysis of Cone Beam Artefact Influences with Respect to Calibration of Metrology Qualified X-Ray Computed Tomography Systems**
Dierck Matern, YXLON International GmbH, DE
- Development of 950 kV X-ray source with small focal spot using a linear accelerator**
Norihito Matsunaga, Nikon Corporation, JP
- Thickness Measurement of Metal Plate Using CT Projection Images and Nominal Shape**
Tasuku Ito, The University of Tokyo, JP
- Realistic Image Synthesis of Imperfect Specimens using Generative Networks**
Deniz Neufeld, Pattern Recognition Lab, Friedrich-Alexander-Universität Erlangen-Nürnberg, DE
- Tools for the Analysis of Datasets from X-Ray Computed Tomography based on Talbot-Lau Grating Interferometry**
Bernhard Fröhler, University of Applied Sciences Upper Austria, AU
- Effect of iterative sparse-view CT reconstruction with task-specific projection angles on dimensional measurements**
Lorenz Butzhammer, Institute of Manufacturing Metrology, Friedrich-Alexander-Universität Erlangen-Nürnberg (FAU), DE
- A low-cost and easy-to-use phantom for cone-beam geometry calibration of a tomographic X-ray system**
Van Nguyen, imec - Vision Lab, Department of Physics, University of Antwerp, Belgium, BE
- A Gaussian filter for complex profile filtration**
Luca Pagani, University of Huddersfield, UK
- Possibilities and Limitations of Automatic Feature Extraction shown by the Example of Crack Detection in 3D-CT Images of Concrete Specimen**
Olaf Paetsch, Zuse Institut Berlin (ZIB), DE
- Mapping Performance of CT**
Nick Brierley, The Manufacturing Technology Centre, UK, UK
- MUSICES - Musical Instrument Computed Tomography Examination Standard: The Final Report Featuring Methods for Optimization, Results of Measurements, Recommendations, Check-lists and Meta-Data Models**
Theobald Fuchs, Fraunhofer Institute Integrated Circuits, Department for X-ray Technology, DE
- Guiding CT Uncertainty Evaluation by the Measurement Realization Process**
Christian Baldo, Federal University of ABC, BR
- Optimisation of surface determination to improve the accuracy and repeatability of detecting unfused powder in AM Aluminum component**
Ahmed Tawfik, Huddersfield University, UK
- Analysis of bone microdamage with Twinned Orthogonal Adjustable Tomograph towards fatigue fracture prevention**
Gerardo Presbítero, Institute of Theoretical and Applied Mechanics, Centre of Excellence Telč, Academy of Sciences of the Czech Republic, CZ
- On nominal-actual comparisons for additive manufacturing applications**
Fabien Léonard, Bundesanstalt für Materialforschung und -prüfung, DE
- An experimental study on segmentation in X-Ray Computed Tomography**
Stefano Petrò, Politecnico di Milano, IT
- Custom-made software tool for the automatic implementation of surface extraction methods based on gradient operators**
Roberto Jimenez-Pacheco, Centro Universitario de la Defensa - Zaragoza, ES
- Comparison of different voxel size calibration strategies**
Marko Katic, FSB, HR

Short Talks

- Back-projection Filtration Image Reconstruction Approach for Reducing Out-of-plane Artifacts in Laminography**
Jeongtae So, Korea Advanced Institute of Science and Technology, KR
- A method and data pipeline for real-time tomographic cross-sections visualization and analysis**
Eusebio Solórzano, Novadep Scientific SL, ES
- Simulation-based sensitivity analysis of geometrical misalignments in X-ray computed tomography systems for dimensional metrology**
Elia Sbettega, University of Padova, IT
- Modelling of focal spot intensity distribution with the aid of spatial resolution limit obtained with star pattern**
Markus Baier, University of Padova, IT

Poster Exhibition

- CT machine geometry changes under thermal load**
Benjamin A. Bircher, Federal Institute of Metrology, METAS, CH
- Comparison of CT and SEM for bone morphometric indices**
Kudakwashe Jakata, Evolutionary Studies Institute, University of the Witwatersrand, ZA
- How to improve mechanical in-situ test during micro-CT measurements**
Jacek Tarasiuk, AGH University of Science and Technology, PL
- Convolutional neural networks for reduction of scatter and beam hardening artefacts in industrial computed tomography**
Ruben Pauwels, Katholieke Universiteit Leuven, BE
- Synchronous dual energy tomography system**
Pablo Pérez, University of Valladolid, ES
- Investigation of positioning accuracy of industrial robots for robotic-based X-ray computed tomography**
Peter Landstorfer, Fraunhofer, DE
- Fast 2-dimensional Contour Reconstruction for Industrial Computed Tomography using Crease Cluster**
Maximilian Wattenberg, Institut für Medizintechnik, Universität zu LübeckInternational GmbH, DE
- Characterization and calibration of high resolution lab-based CT system with small field of view**
Pavel Blažek, Central European Institute of Technology, CZ
- Suppression of residual gradients in the flat-field corrected images**
Michal Vopalensky, Institute of Theoretical and Applied Mechanics, Centre of Excellence Telc, Czech Academy of Sciences, CZ
- CAD-based defect inspection with optimal ROI selection based on polychromatic X-ray projection images**
Alice Presenti, University of Antwerp, BE
- Report of the Progress on a Laboratory X-Ray Source Based Computed Tomographic System at 9.25 keV**
Dominik Müller, University of Würzburg, DE
- Verifying the measurement accuracy for X-ray cone-beam CT scans of objects smaller than 5 mm diameter**
Daniel Weiss, Carl Zeiss IMT GmbH, DE
- Combined use of HeliScan µCT, ELITE and FIB-SEM systems for multi-modal and multi-resolution manufacturing quality control**
Grzegorz Pyka, Thermo Fisher Scientific, CZ
- Lab-based Diffraction Contrast Tomography (LabDCT) for Materials Microstructure Characterization in Industry Applications**
Christian Holzner, Xnovo Technology ApS, DE
- Porosity determination in additively manufactured Ti parts using X-ray tomography**
Jonathan Glinz, University of Applied Sciences Upper Austria, AU
- X-ray CT on modeling steel parts made by selective-laser-melting**
Ramil Gainov, Institute ZEA-1, Forschungszentrum Jülich GmbH, DE
- Characterization of the effects of detector angular misalignments and accuracy enhancement of X-ray CT dimensional measurements**
Valentina Aloisi, North Star Imaging, US
- Utilization of single point uncertainties for geometry element regression analysis in dimensional X-ray computed tomography**
Andreas Michael Müller, Institute of Manufacturing Metrology, Friedrich-Alexander-Universität Erlangen-Nürnberg, DE
- High Energy 750kV Microfocus X-ray Sources for Quality Control on Large Metal Printed Parts**
David Bate, Nikon Metrology, UK
- Non-destructive testing of microelectronic devices using a laboratory multipurpose diffractometer**
Natalia Dadivanyan, Malvern Panalytical B.V., NE
- Geometry Compensation of 3DPrinted Parts**
Gerd Schwaderer, Volume Graphics GmbH, DE
- A Curvelet based Sinogram Correction Method for Metal Artifact Reduction**
Kiwan Jeon, National Institute for Mathematical Sciences, KR
- Fusion of the XCT, XRF and back scattered data to characterize multi-layer coating of the middle age artifact**
Daniel Vavrik, Institute of Theoretical and Applied Mechanics, CZ
- Evaluation of the uncertainties in X-ray spectral estimation using transmission measurements**
Wenchao Cao, Katholieke Universiteit Leuven, BE
- X-ray sources for high throughput and extreme resolutions**
Emil Espes, Excillum AB, SE
- Validation of a Method for the Optimization of Scan Parameters for Measuring with Computed Tomography**
Raoul Christoph, TU Dresden, Werth Messtechnik GmbH, Deutsches Krebsforschungszentrum, DE
- Optimization of multiple axes control for metal artifact reduction in X-ray CT**
Toru Kano, Tokyo University of Technology, Shinshu University, JP
- Roughness Investigation of SLM Manufactured Conformal Cooling Channels Using Computed Tomography**
Christopher Klingaa, Technical University of Denmark, DE
- A versatile and compact laminography/tomography system**
Pablo Pérez, University of Valladolid, ES
- 15 MeV CT for very large objects**
Nicolas Estre, The French Alternative Energies and Atomic Energy Commission (CEA), FR

Poster Exhibition

- An attempt to detect anomalies in CT-data of car body parts using machine learning algorithms**
Thomas Schromm, BMW AG, DE
- CCD and scientific-CMOS detectors for submicron laboratory based X-ray Computed tomography**
Jakub Salplachta, Central European Institute of Technology, Brno University of Technology, CZ
- Microstructural analysis of cement materials by lab and beamline techniques**
Luca Valentini, University of Padova, IT
- Effect of gravity on porosity and surface roughness of SLM IN-625 parts**
Tobias Thiede, Bundesanstalt für Materialforschung und -prüfung, DE
- Spot size and detector unsharpness determination for numerical measurement uncertainty determination**
Christian Orgeldinger, Institute of Manufacturing Metrology, Friedrich-Alexander-Universität Erlangen-Nürnberg (FAU), DE
- Self-calibrating helical micro-CT and computed tomography dimensional measurements**
Trond Varslot, Thermo Fisher Scientific, CZ
- Morphological study of defects in laminated joints of composite materials using microCT**
Cintia Guimarães Ferreira, Nuclear Engineering Program, Nuclear Instrumentation Laboratory, COPPE/UFRJ, BR
- Case studies of predictive analysis and casting process optimization based on CT scans**
Marco Giogoli, Metrix3D, IT
- Using CT to Image and Investigate the Effect of Low-Velocity Impact Damages on the Structure of Fiber Reinforced Polymer Samples**
Christian Baldo, Federal University of ABC, BR
- Error Investigations for a CT and Additive Manufacturing based Reverse Engineering Workflow**
Fabian Bauer, Siemens Corporate Technology, DE
- 300kV Open Type Microfocus X-ray source for Industrial X-ray CT**
Masayuki Hirano, Hamamatsu Photonics K.K., JP
- Synthesis and characterization of metal-ceramic composite 316L/sycro**
Haimon Alves, State University of Rio de Janeiro, BR
- Shape analysis for grains and pores on 3d digital images**
Fabian Biebl, Math2Market GmbH, DE
- Study of keyhole-porosities in selective laser melting using X-ray computed tomography**
Aditi Thanki, Katholieke Universiteit Leuven, BE
- Automated ROI Localization On Tomographic Projections**
Marina Chukalina, Shubnikov Institute of Crystallography FSRC "Crystallography and Photonics" RAS, RU
- 3-in-1 X-ray Computed Tomography**
Nathanael Turner, The Manufacturing Technology Centre, UK
- Is the metrotomography a reliable method to measure the dimensional and geometric specifications of technical parts? CT machine versus CMM machine - A practical approach**
Fernando Ferreira, CATIM - Technological Center for the Metal Working Industry, PT
- Infrared thermography and method of finite elements applied to thermal nondestructive characterization in rails networks**
Sougrati Belattar, Cadi Ayyad University, Faculty of sciences, MA
- Understanding and improving ultrasonic inspection of the forging titanium alloy**
Teodor Tranca, DIAC SERVICII srl, RO
- On the impact of probing errors on form measurement in Computed Tomography**
Filippo Montanari, Technical University of Denmark, DK
- On the systematic design of calibration artefacts for Computed Tomography**
Leonardo De Chiffre, Technical University of Denmark, DK
- X-ray and FTIR μ -CTs for morphological and chemical characterization of eco-sustainable insulating foams**
Sandro Donato, Universita' degli Studi di Trieste, INFN Trieste, IT